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Application No.	Applicant(s)	
09/912,188	BAILEY ET AL.	
Examiner	Art Unit	
Ouoc A Tran	2176	

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Class	Subclass	Date	Examiner
715	846	12/22/2004	8
715	513	12/22/2004	Ø
707	9	12/22/2004	(8)
705	27	12/22/2004	8
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Inventor searcg check for double patent, US-PAT, US-PGPUB, EPO, JPO, Derwent, IBM_TDB, Internet search, Plus search, EIC	12/22/2004	<b>a</b>
Personal Digests	12/22/2004	2